

<b>Notice of References Cited</b>	Application/Control No. 10/538,540	Applicant(s)/Patent Under Reexamination MIHAN ET AL.	
	Examiner Rip A. Lee	Art Unit 1713	Page 1 of 1

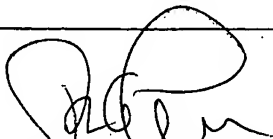

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,498,581 A	03-1996	Welch et al.	502/102
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	C	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*	N	WO 01/92346 A2	12-2001	International	Wang	C08F 10/00
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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